Notice of References Cited Application/Control No. 10/770,074 Examiner Toan M. Le Applicant(s)/Patent Under Reexamination HAY, JENNIFER Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,460,012	10-2002	Welch et al.	702/182
*	В	US-6,778,916	08-2004	Lee, Hyung Yil	702/42
*	С	US-5,546,797	08-1996	Dutta et al.	73/150A
*	D	US-4,635,471	01-1987	Rogers et al.	73/81
*	E	US-2003/0234595	12-2003	Takahashi et al.	310/324
*	F	US-2002/0104371	08-2002	Gitis et al.	73/81
*	G	US-6,634,236	10-2003	Mars, William Vernon	73/799
*	Н	US-4,667,509	05-1987	Tobolski et al.	73/83
	ı	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	α					
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Hay et al., Instrumented Indentation Testing, 2000, ASM Handbook Vol. 8: Mechanical Testing and Evaluation
	v	
	w	
	×	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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